# SUPERALLOWED $0^+ \rightarrow 0^+$ BETA DECAY

#### **BASIC WEAK-DECAY EQUATION**

$$ft = \frac{K}{G_v^2 < >^2}$$

f = statistical rate function:  $f(Z, Q_{EC})$  t = partial half-life:  $f(t_{1/2}, BR)$   $G_v$  = vector coupling constant < > = Fermi matrix element





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#### INCLUDING RADIATIVE AND ISOSPIN-SYMMETRY-BREAKING CORRECTIONS



THEORETICAL UNCERTAINTIES 0.05 - 0.10%

# WHAT CAN WE LEARN?

#### FROM A SINGLE TRANSITION

Experimentally determine  $G_v^2(1 + R)$ 

$$\mathcal{T}t = ft(1 + i_{R})[1 - (i_{C} - i_{NS})] = \frac{K}{2G_{V}^{2}(1 + i_{R})}$$

#### FROM MANY TRANSITIONS

Test Conservation of the Vector current (CVC)

Validate the correction terms

Test for presence of a Scalar current

# **7***t* values constant

#### WITH CVC VERIFIED

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#### WITH CVC VERIFIED

a Scalar current



Obtain precise F PRIOR Determine SIBLE ATISFIED T + Determine SIBLE ATISFIED T + NUV POONS SATISFIED T + ONUV POONS SATISFIED T + ONUV POONS SATISFIED T + ONUV POONS SATISFIED T +

 $V_{ud}^{2} = G_{v}^{2}/G^{2}$ 

$$V_{ud}^2 + V_{us}^2 + V_{ub}^2 = 1$$

R

#### **CKM MATRIX AND UNITARITY**



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#### **PRECISION REQUIRED FROM EXPERIMENT**

$$7t = ft(1 + '_{R})[1 - (_{C} - _{NS})] = \frac{K}{2G_{V}^{2}(1 + _{R})}$$



#### **GUIDELINES FOR PRECISION MEASUREMENTS**

- Experimental apparatus should be as simple as possible.
- All experimental parameters must be under control and testable.
- Experimental equipment should be dedicated only to this measurement.
- Calibration is often the most important part of the measurement.
- Tests for sources of systematic error must dominate data acquisition.
- Redundancy is desirable in both measurement and analysis.
- No inconsistencies can be overlooked.
- A complete error budget is the most important part of the result.











## **REQUIREMENTS FOR PRECISE HALF-LIFE MEASUREMENT**

#### **IMPORTANT FEATURES**

- Extremely high source purity -- separation by Z/A and range.
- Very low background
- Rapid transport (130 ms) to shielded counting position.
- Dominant dead-time, fixed and measured.



- Repeated measurements under different experimental conditions.
- Decay data stored cycle-by-cycle so actual instantaneous rate can be used in analysis.
- Precise statistical procedures used, including simultaneous fit to many cycles with single half-life.















#### **BRANCHING-RATIO MEASUREMENTS**







#### **HPGe DETECTOR CALIBRATION**

#### **Commercial standard sources:**

**Relative intensities not known in any case to better than 0.4%.** 

Source activity (absolute intensity) can be specified to 2-5%; rarely to 1%.

For higher precision:

Source activity for certain cases can be measured to 0.1% by 4 coincidence counting; in our case <sup>60</sup>Co at PTB Lab. ←



Use clean -ray cascades; home-made sources.

**Combine Monte Carlo calculations with measured points.** 

#### **KEY RADIOACTIVE SOURCES**



#### EG&G ORTEC Gamma-X HPGe



#### DIMENSION

#### NOMINAL

Crystal radius, R	34.95 mm
Crystal active length, $L - t_{f} - t_{b}$	77.7 mm
Cap face to crystal distance, D	5.6 mm
Hole radius, r	5.8 mm
Hole depth, d	69.7 mm
Depth internal (Li) dead layer, t <sub>1</sub>	>1 mm
Depth front dead layer, t <sub>f</sub>	>0.3 m

#### X-ray picture of crystal



#### EG&G ORTEC Gamma-X HPGe



#### X-ray picture of crystal

#### **Crystal side-scan**







#### EG&G ORTEC Gamma-X HPGe

X-ray picture of crystal

**Crystal side-scan** 

**Distance ratio for <sup>57</sup>Co** 





#### EG&G ORTEC Gamma-X HPGe

X-ray picture of crystal

**Crystal side-scan** 

**Distance ratio for <sup>57</sup>Co** 

#### **Fitted for energy dependence**



## DETECTOR EFFICIENCY 50 keV < E < 1.4 MeV

#### Source measurements



10 sources recorded -

4 key sources, 3 locally made, have pure cascades

<sup>60</sup>Co source from PTB with activity known to ± 0.1%

<sup>60</sup>Co
<sup>109</sup>Cd
<sup>88</sup>Y
<sup>108m</sup>Ag
<sup>120m</sup>Sb
<sup>134</sup>Cs
<sup>137</sup>Cs
<sup>180m</sup>Hf
<sup>48</sup>Cr
<sup>133</sup>Ba





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● <sup>133</sup> Ba

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A88Y

#### Source measurements

#### *vs* unscaled Monte Carlo calculations (CYLTRAN)

Physical properties and location of HPGe crystal measured precisely

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<sup>60</sup>Co source from PTB with activity known to ± 0.1%





#### **DETECTOR CHARACTERIZATION - DETAILS**

Efficiency extended up to 3.5 MeV



Helmer et al., Appl. Rad. Isot. 60, 173 (2004).

#### **DETECTOR CHARACTERIZATION - DETAILS**



# **BETA-DECAY BRANCHING OF <sup>34</sup>Ar**









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### **BRANCHING-RATIO RESULTS**

Where no ground-state decay occurs, a -ray spectrum and relative efficiencies are enough to obtain branching ratios to  $\pm 0.2\%$ .

Hardy et al., PRL 91, 082501 (2003).





Where superallowed branch feeds the ground state, we measure the other branching ratios to  $\pm 0.2\%$ and subtract them from 100%. In favorable cases (like <sup>34</sup>Ar) the result can be good to  $\pm 0.01\%$ .

## PENNING TRAP Q<sub>EC</sub>-VALUE MEASUREMENTS



# PENNING TRAP Q<sub>EC</sub>-VALUE MEASUREMENTS

# **IGISOL System**



Or for the full Penning trap Q-value story: Tommi Eronen, Jyvaskyla Research Report No. 12/2008 (Thesis)